

A Phase Diversity Sensor to Measure Piston Misalignment on the Keck II Segmented Mirror

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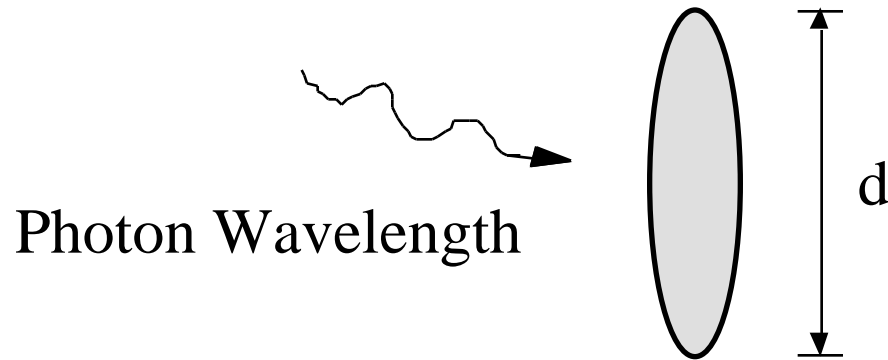
- Motivation (Relevance to Space Programs)
- Introduction to Phase Diversity
- Phase Diversity Sensor Design
- Experiment Layout (Drawings)
- Experiment Installation on Keck II
- Summary

Scaling of a Mirror or Lens

Want to change:

$$\frac{\$ \text{ (Performance)}}{\$ \text{ (Cost, Size, Weight, Power)}}$$

Scaling of a Mirror or Lens

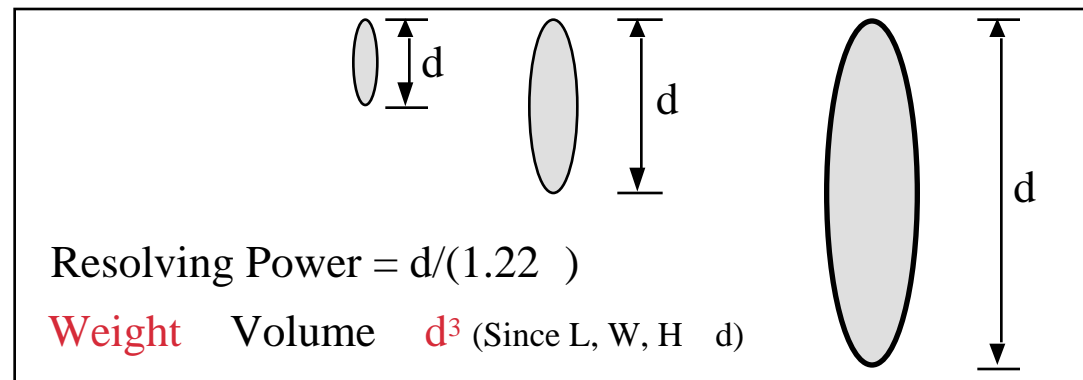


Performance – Resolving Power = $d / (1.22 \lambda)$

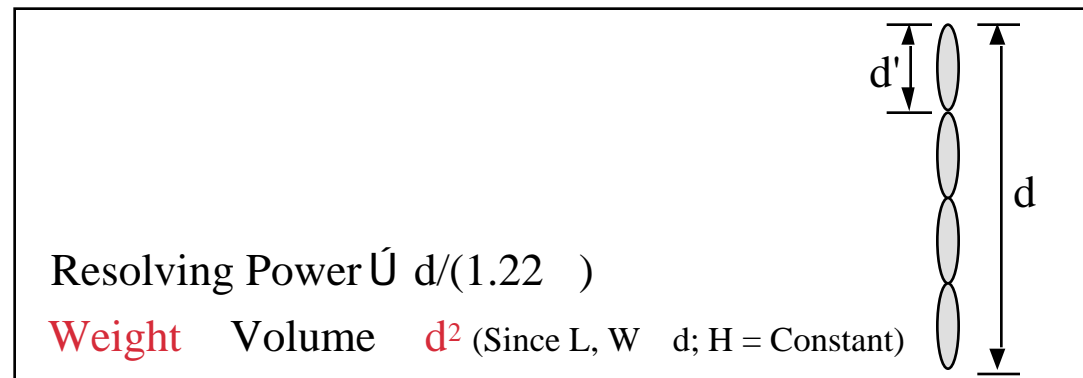
Cost – Size – Weight – $(d)^3$

Advantages of a Multiple Aperture or Sparse Aperture Mirror / Lens

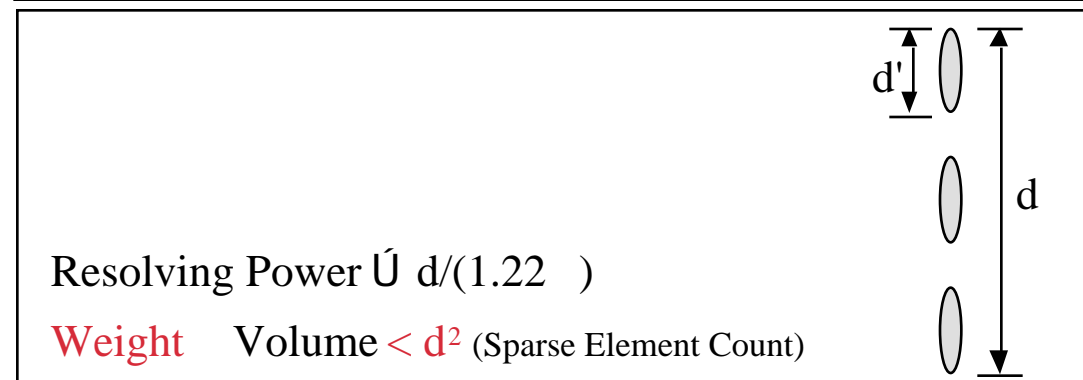
Simple Mirror or lens



Multiple Aperture Advantage



Sparse Aperture Advantage



Problem:

How does one align a multiple or sparse aperture mirror in a telescope?

Solution:

1. Generate a reference beam to measure tilt and piston
 - a. Artificial guide star with a Hartmann sensor
 - b. Outgoing wave front interferometer
2. Use photons from viewed object
 - a. Hartmann Sensor / Edge Sensors (Tilt / Piston)
 - b. Shearing Interferometer
 - c. Utilize an approach called Phase Diversity (PD)

1. Generate a reference beam to measure tilt and piston
 - a. Artificial guide star with a Hartman sensor
 - b. Outgoing wave front interferometer

→ **A locally generated reference beam adds complexity, weight, and cost to an imaging system.**

2. Use photons from viewed object
 - a. Hartmann Sensor / Edge Sensors (Tilt / Piston)
 - b. Shearing Interferometer

→ **Require reimaging optics which add complexity, weight, and cost.**

- c. Utilize a technique called Phase Diversity (PD)

→ **System presented today**



Many NGST design concepts rely on segmented primary mirrors (GSFC)

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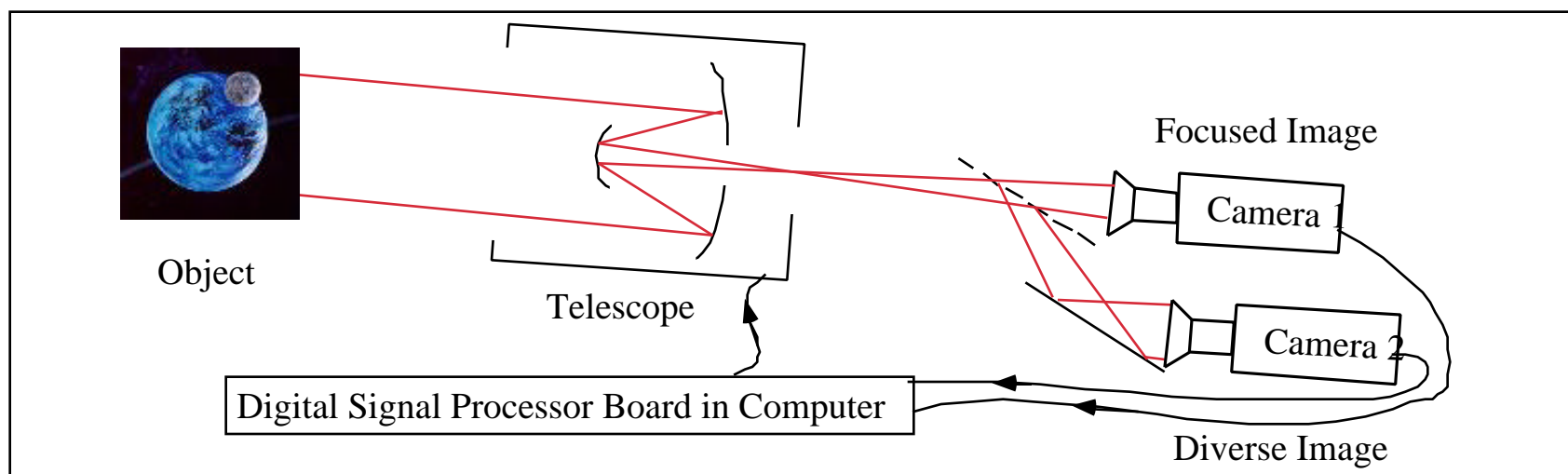
Introduction to Phase Diversity

Phase Diversity Technique:

- a. Collect an in-focus image
- b. Collect an out-of-focus (diverse) image



- c. Utilize a phase diversity algorithm to measure the wavefront error.



Introduction to Phase Diversity

Algorithm Design:

A variety of Phase Diversity algorithms are in use today

---> all are scene independent

- a. ERIM - Paxman, Seldin,
- b. Stockholm Observatory - Löfdahl, Sharmer
- c. Lockheed Martin (GRNN) - Kendrick, Acton, Duncan, ...

Basic to all algorithms:

Let: $Q(f)$ = Fourier Transform of Object
 $S_0(f)$ = Fourier Transform of Focused Image
 $S_d(f)$ = Fourier Transform of Defocused Image
 $H_0(f)$ = Optical Transfer Function (OTF) of Focused System
 $H_d(f)$ = OTF of Defocused System

Introduction to Phase Diversity

Minimize a metric similar to the Golsalves metric.

$$E = \frac{|S_0(f) \hat{H}_d(f) - S_d(f) \hat{H}_0(f)|^2}{|\hat{H}_0(f)|^2 + |\hat{H}_d(f)|^2} \quad \begin{array}{l} (^{\wedge}) \text{ denotes the OTFs} \\ \text{are working estimate} \end{array}$$

Generate Sharpness and Power Metrics

Solve using a General Regression Neural Network

$$\text{Sharpness Metric} = \frac{S_0(f) S_d^*(f) - S_0^*(f) S_d(f)}{S_0^*(f) S_0(f) + S_d^*(f) S_d(f)}$$

$$\text{Power Metric} = \frac{S_0(f) S_0^*(f) - S_d(f) S_d^*(f)}{S_0(f) S_0^*(f) + S_d(f) S_d^*(f)}$$

Introduction to Phase Diversity

GRNN: General Regression Neural Network

Solve for Y_0 given an N element training set.

$$Y_0 = \frac{\sum_{i=1}^N Y_i \exp(-R_i^2 / \sigma^2)}{\sum_{i=1}^N \exp(-R_i^2 / \sigma^2)} \quad \text{where, } R_i^2 = (X_i - X_0)^T (X_i - X_0)$$

R_i = Euclidean distance from X_0 to each of the X_i points.

- determines the width of influence of each data point.

(X_i, Y_i) is a training set pair: X_i = Metric, Y_i = Aperture Configuration

(X_0, Y_0) : X_0 = Measured Metric, Y_0 = Calculated Configuration

--> Detailed algorithm design is a topic of the next talk <--

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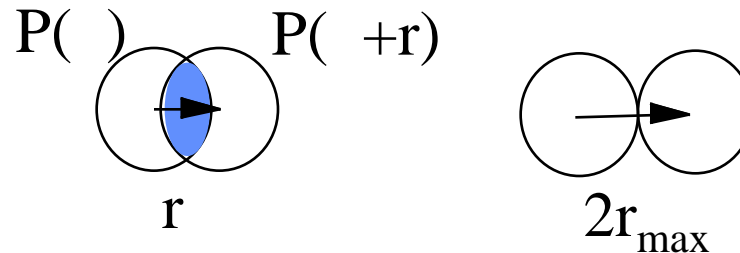
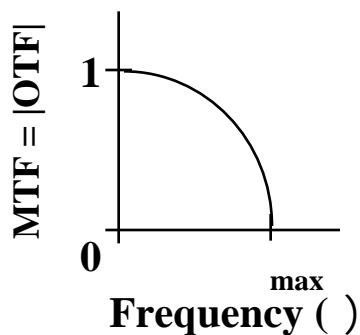
Phase Diversity Sensor Design

Design Issues:

1. Critical Sampling on Camera Pixels (F# of system)
2. Amount of Defocus
3. Sensor Optics Layout
4. Optical Designs (Telecentric)
5. Acquisition Parameters:
 - a. Filter Spectral Bandwidth (nm)
 - b. Camera Shutter Speeds (ns)
 - c. Neutral Density Filters
6. Environment (High Altitudes, Low Temperatures)

Critical Sampling of Images

Require camera to critically sample the images:



$P() = \text{Pupil Function}$

Math:

$OTF = H() = Ap(d_i)$, where $d_i = \text{image dist.} = f$ (for an object at ∞)

Now: $MTF = 0$ at f_{\max}
 $\implies Ap(f_{\max}) = Ap(2r_{\max}) = 0; \implies f_{\max} = 2r_{\max}$

Critical sampling: $f_{\max} = 1/(2h_{\max})$, $h = \text{pixel pitch}$ (Nyquist Theorem)

Airy Disk Diameter $= 2.44 f/2r_{\max} = 2.44 f / (f_{\max}) = 4.88 h_{\max}$

$\implies \text{Airy Disk Diameter} = 4.88 * \text{Pixel Pitch}$

Critical Sampling on Camera Pixels

Critical sampling occurs when the Airy disk diameter is sampled by 4.88 pixels

Set: $4.88 = \text{Airy disk diameter} / \text{pixel pitch} = [2.44 * (F/\#) * \lambda] / [h]$
where h is the pixel pitch

Given λ , h:

For critical sampling or better: $(F/\#) > 2 h / \lambda$

For the 900 nm sensor with 6.8 μm pixels: $(F/\#) > 2 h / \lambda = 15.1$

For the 1662 nm sensor with 50 μm pixels: $(F/\#) > 2 h / \lambda = 61.7$

Note: (If Define: $Q/\# = (\lambda / D) * (f/h)$, then $Q/\# = 2$ corresponds to critical sampling).

Phase Diversity Amount of Defocus

The amount of defocus at the two wavelengths is determined from:

1. Simulations
2. Empirical Data from Processing Images

For the two sensors described above:

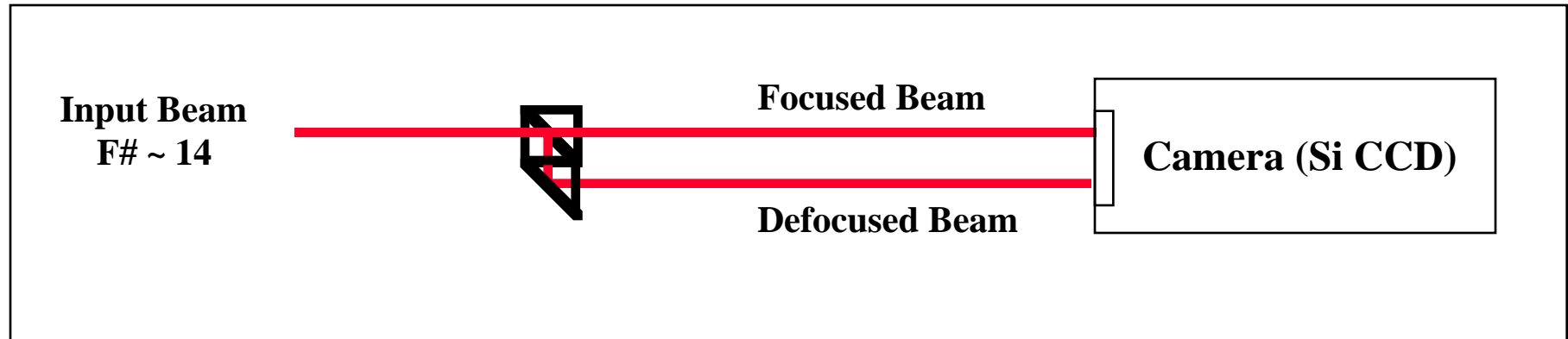
1. At 900 nm, 1.9 waves of defocus was used
2. At 1662 nm, 1.0 waves of defocus was used

$$\text{Number of waves of defocus} = Z / [8 (F/\#)^2]$$

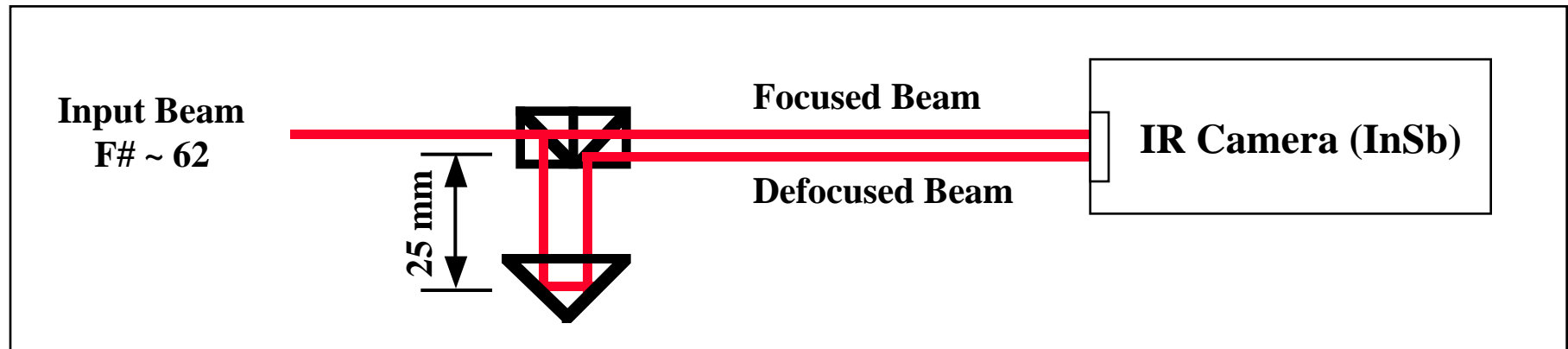
where, Z = displacement along the optical axis

Phase Diversity Sensor Optics Layout

Phase Diversity Sensor 1: ($F\# = 15$, Camera pixel pitch = $6.8 \mu\text{m}$, $\lambda = 900\text{nm}$)

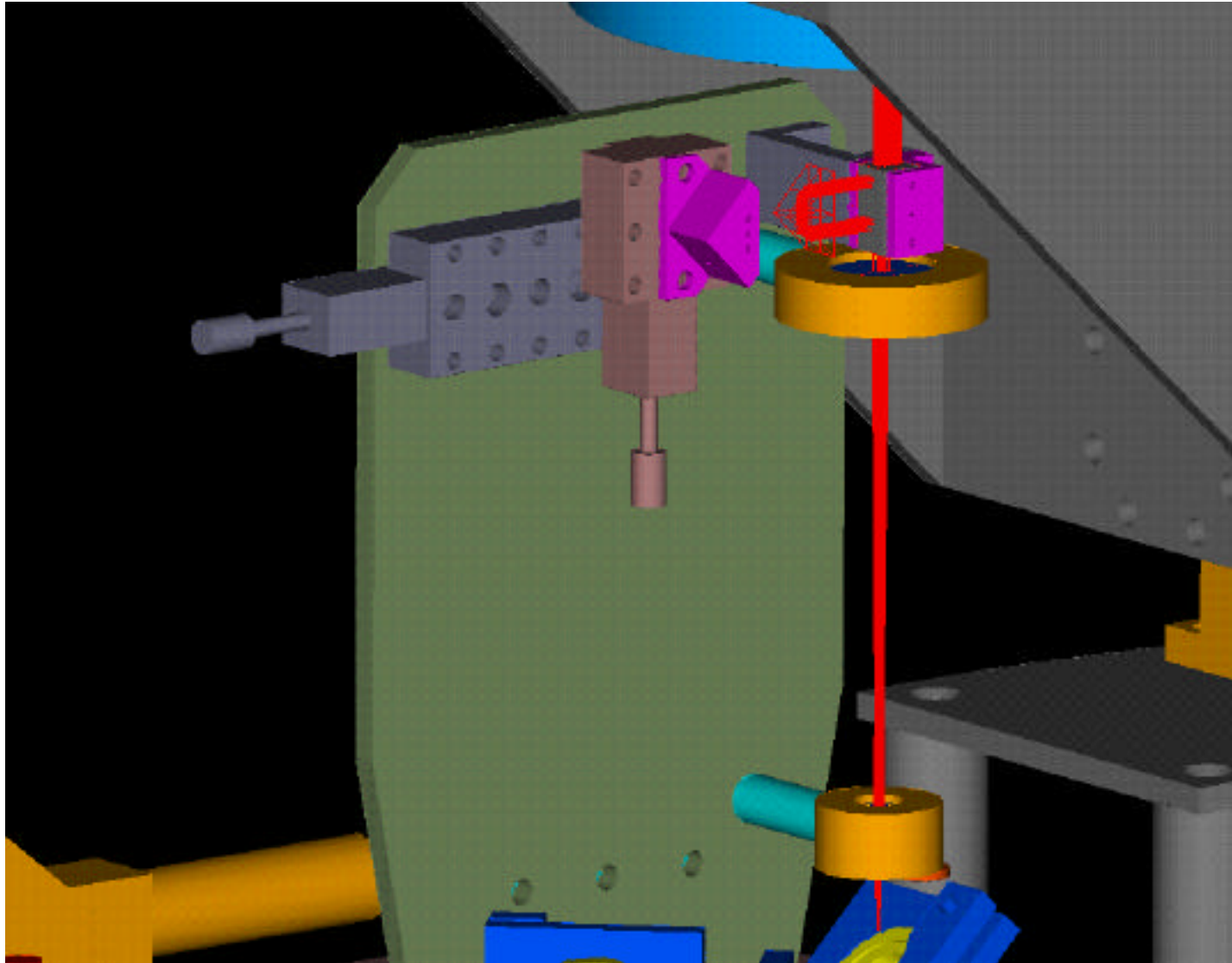


Proposed Phase Diversity Sensor 2: ($F\# = 62$, Camera pixel = $50.0 \mu\text{m}$, $\lambda = 1662\text{nm}$)



Only one camera is needed for each PD sensor; both beams projected onto same array.

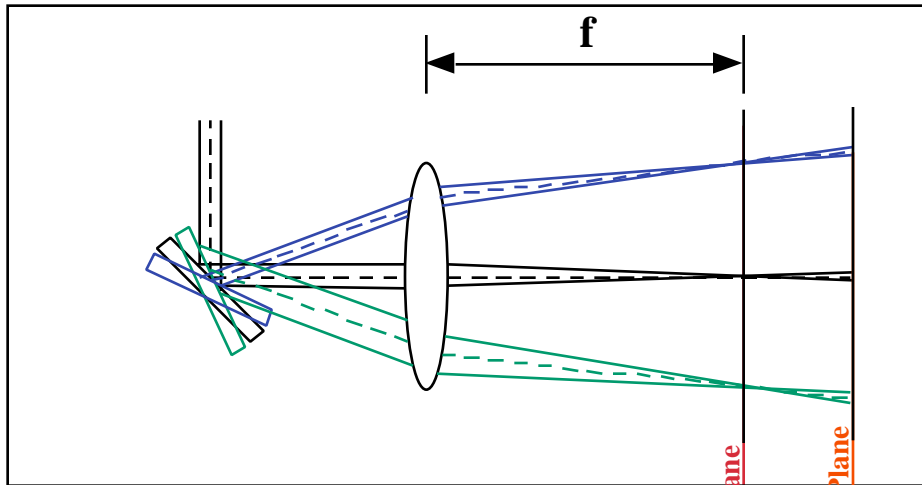
PD Sensor (1662 nm)



Side View

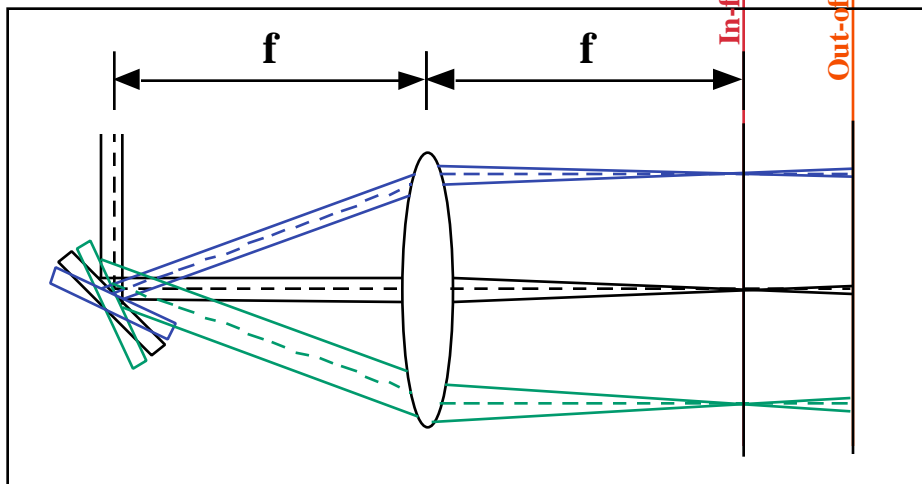
Optical Designs (Telecentric)

Normal (Scanner):



Size of in-focus image
Size of out-of-focus image

Telecentric (Scanner):



Size of in-focus image
= Size of out-of-focus image

A “Telecentric Stop” may also be used.

Acquisition Parameters

Filter Spectral Bandwidth (nm)

- filter bandwidth is 10 nm (at a pass wavelength of 900 nm)
- dispersion < 0.002 arcseconds when 20 degrees off the zenith
- this is less than 10 % of the diffraction spot size
- this results in about a 10 % elongation of the diffraction-limited PSF
- will view objects less than 20 degrees off the zenith

Camera Shutter Speeds (ns)

- Keck studies of speckle use 134 ms exposures at $\lambda = 2.2 \mu\text{m}$
- at $\lambda = 900 \text{ nm}$ this corresponds to about 55 ms exposures
- \Rightarrow use exposures less than 50 ms
- On Photometrics camera, the minimum exposure time is 14 ms

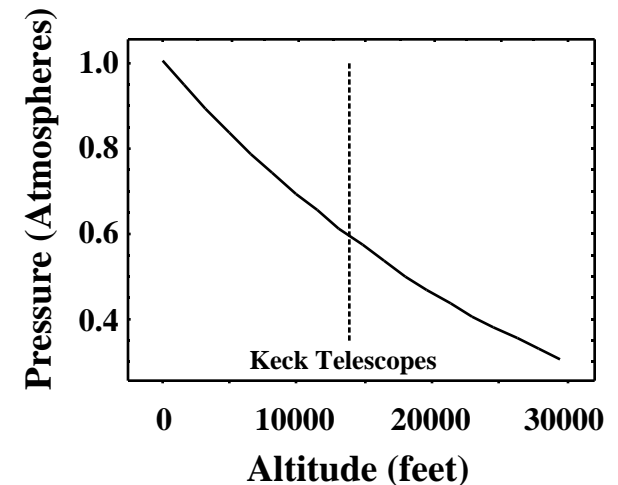
Neutral Density Filters

- use neutral density filter set to adjust exposure
- Fused Silica, Surface Flatness: 2λ per 25 mm
- Set contains: Nominal Densities of 0.03, 0.1, 0.3, 0.5, 1.0, 2.0, 3.0

Environmental Effects

High Altitude (13,780 feet)

- Most hard drives not rated above 10,000 feet
- Mountain Optech
 - High altitude magnetic hard drive
 - 2.0 GByte
 - Rated to 20,000 feet
- Pinnacle Micro: Magneto-Optical Drive
 - Vertex 2.3 GByte
 - Two sided cartridges
 - Store 1.15 GByte / Side
 - Rated to 20,000 feet

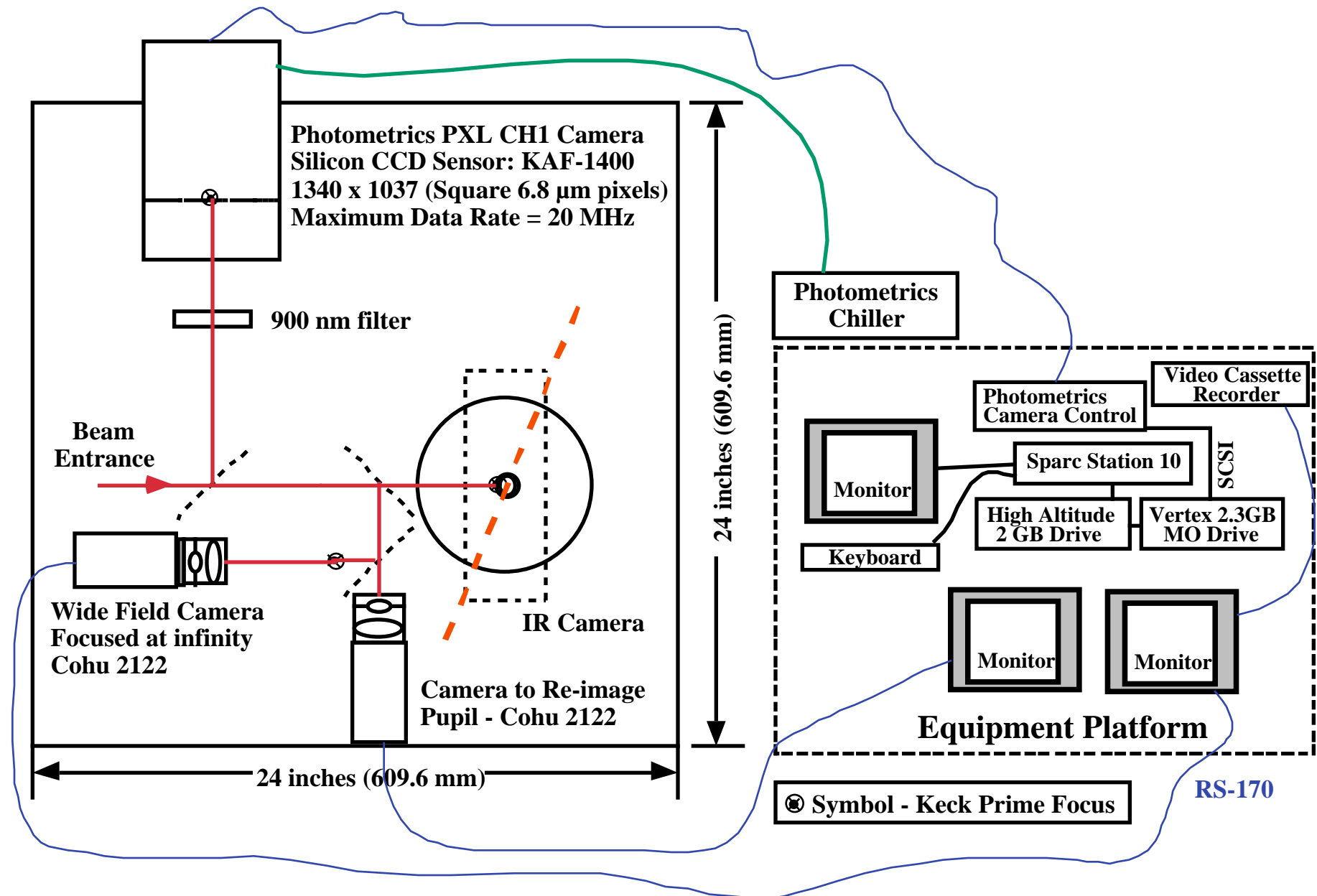


Low Ambient Temperatures (-5 °C)

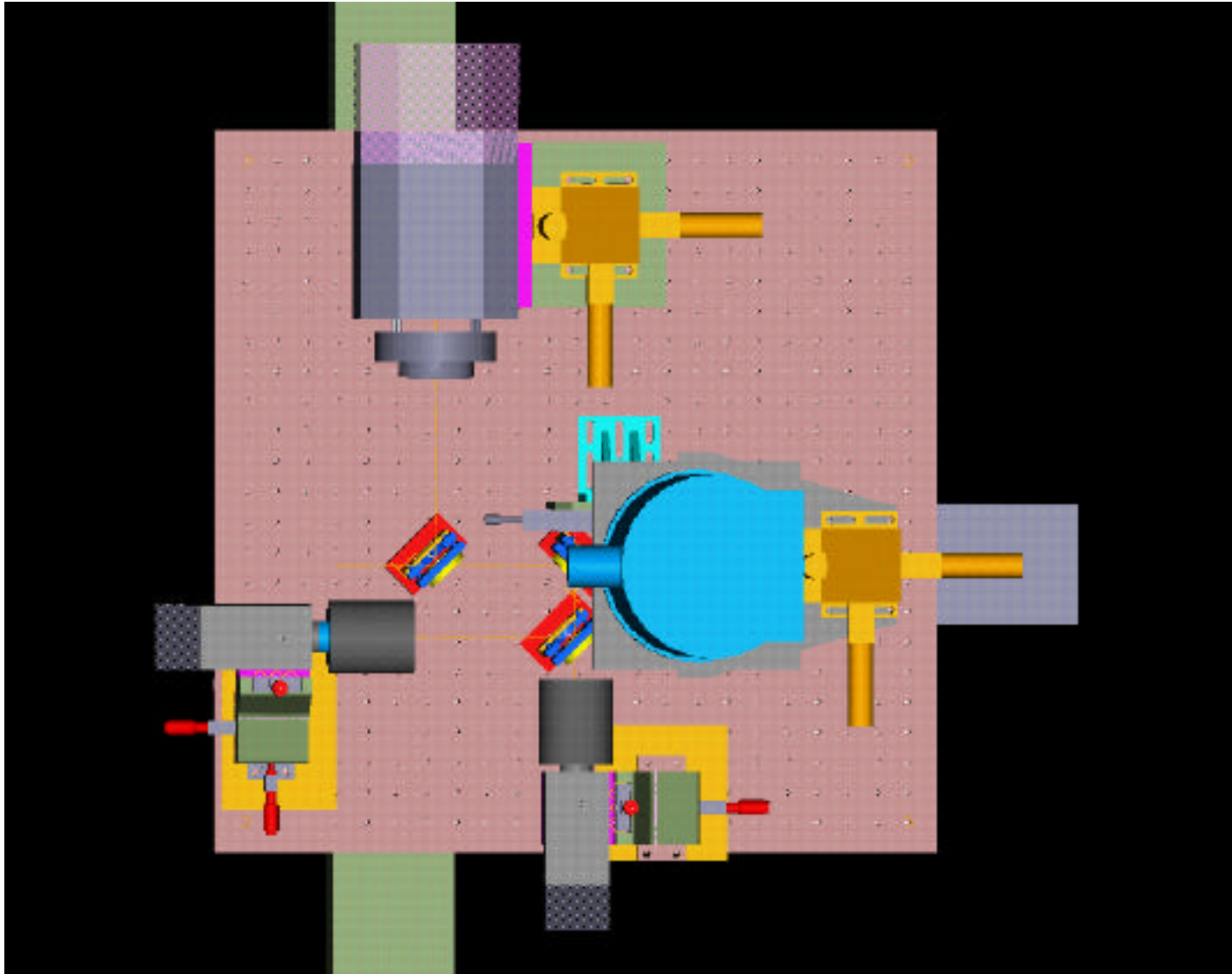
- All equipment functioned at these temperatures

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Experiment Schematic

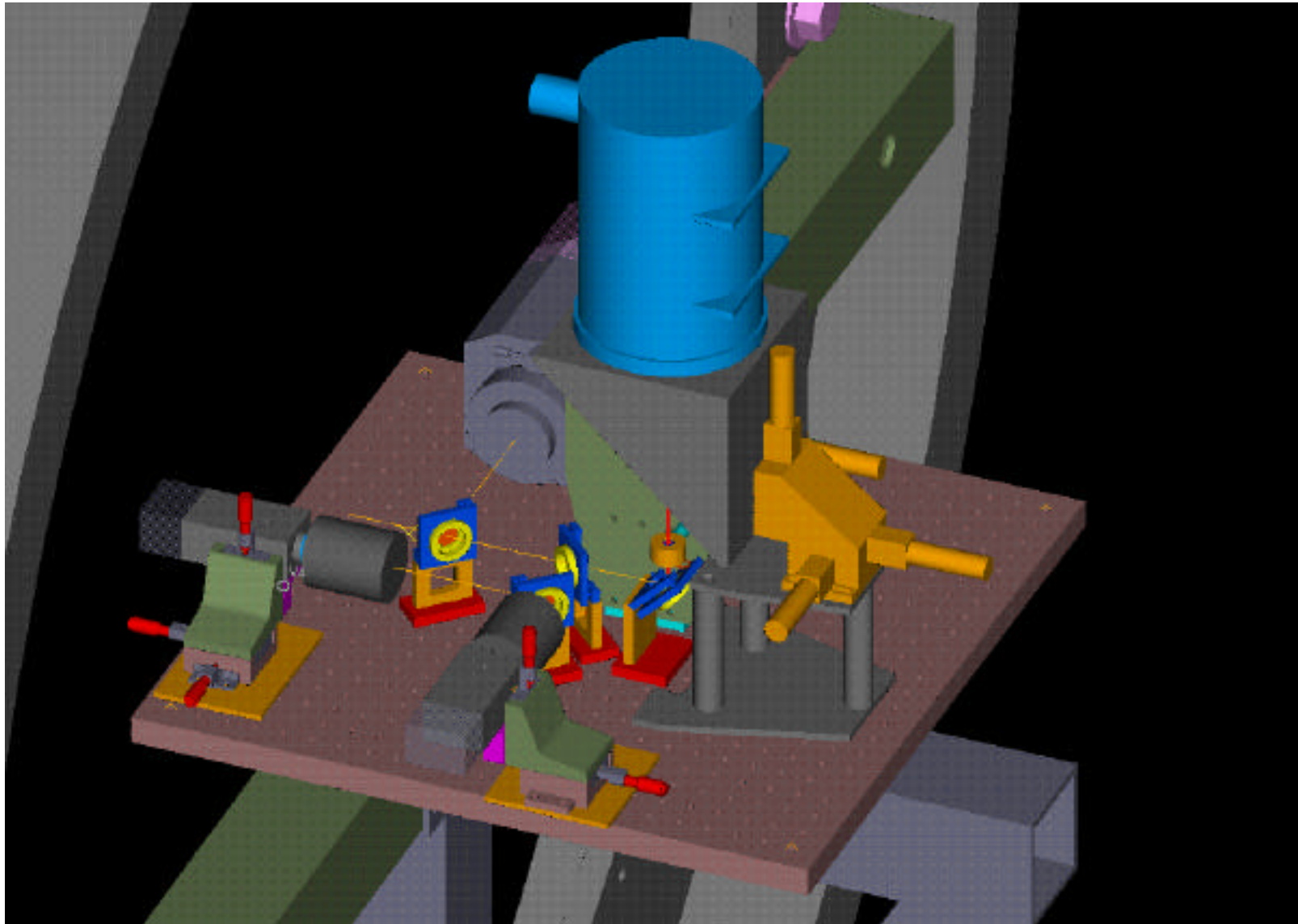


Experiment Layout



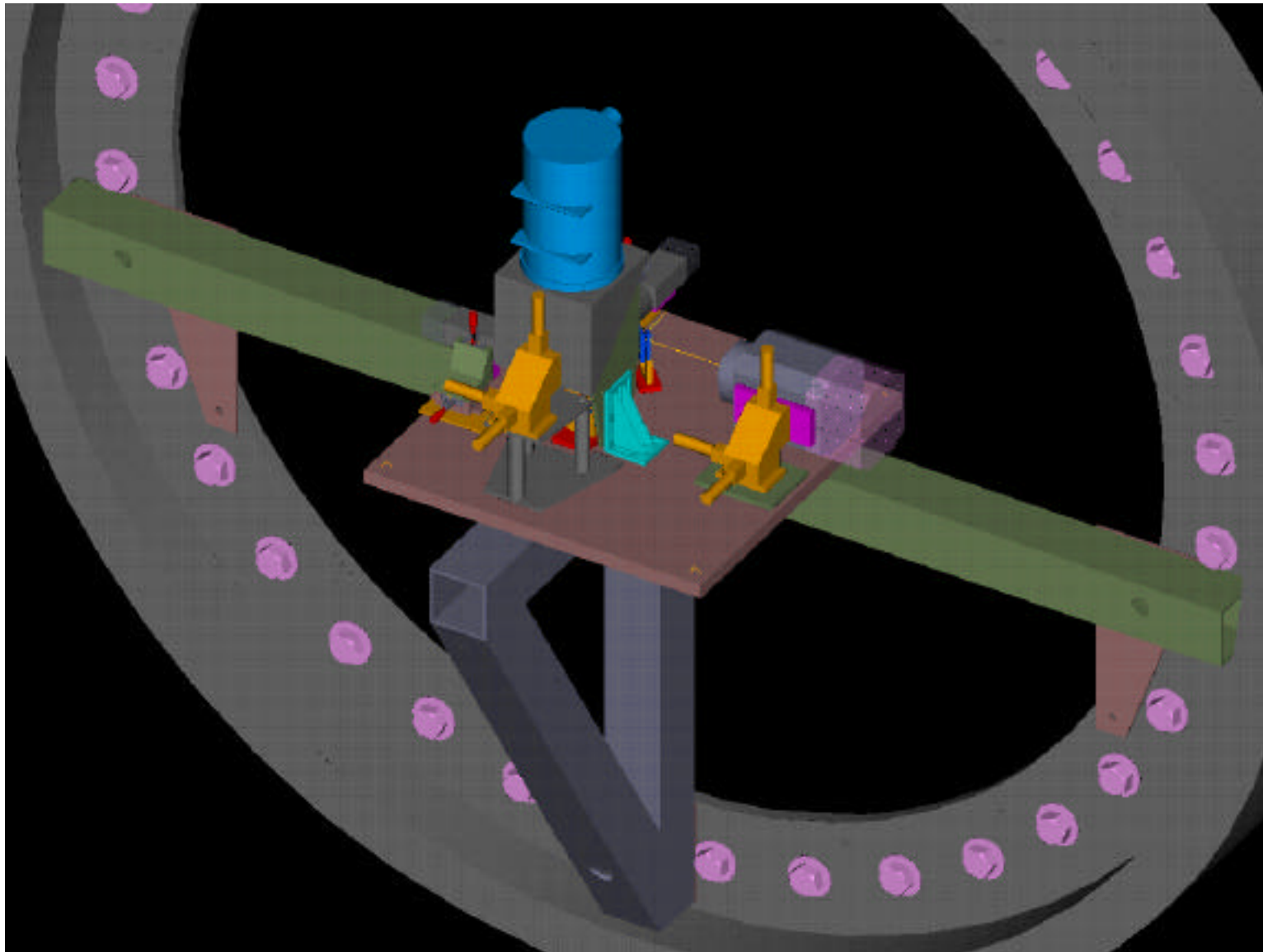
Top View

Experiment Layout



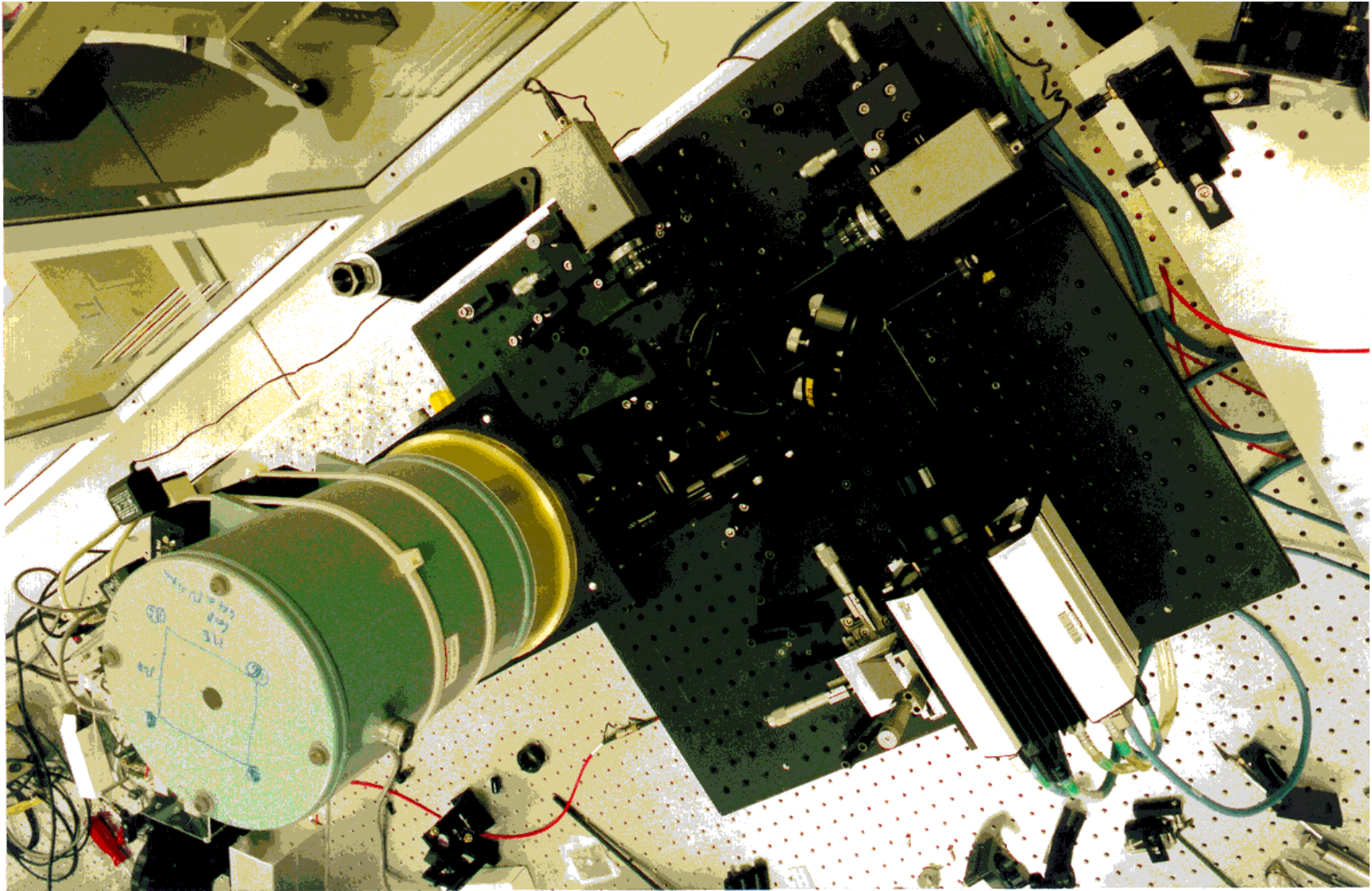
Top-Side View

Breadboard Mounting to Left Nasmyth Platform of Keck II



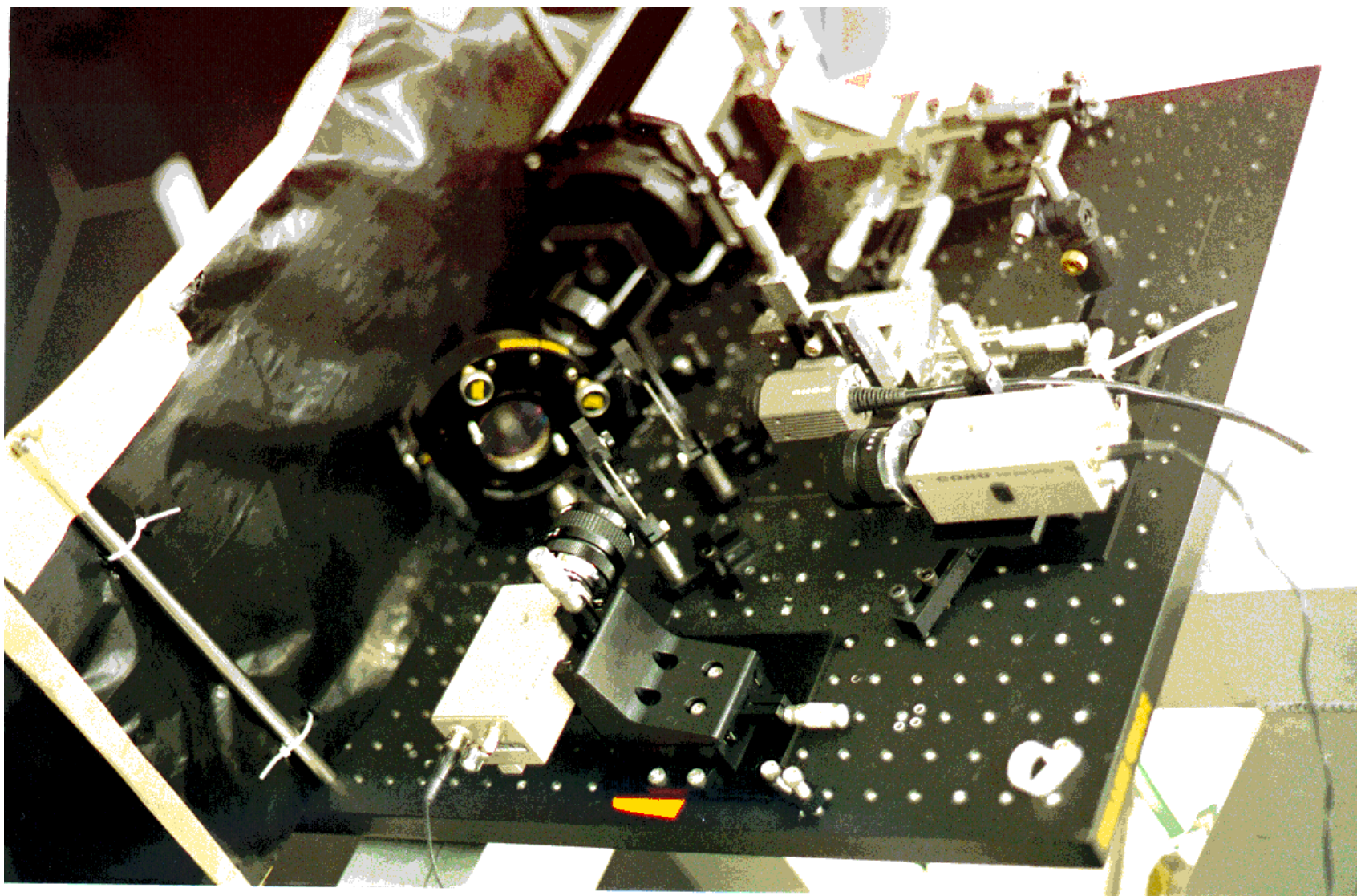
Top-Side View

Photo: Optical Breadboard



Top View

Photo: Optical Breadboard



Top Side View

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Primary Mirror Focal Length = 17.5 meters

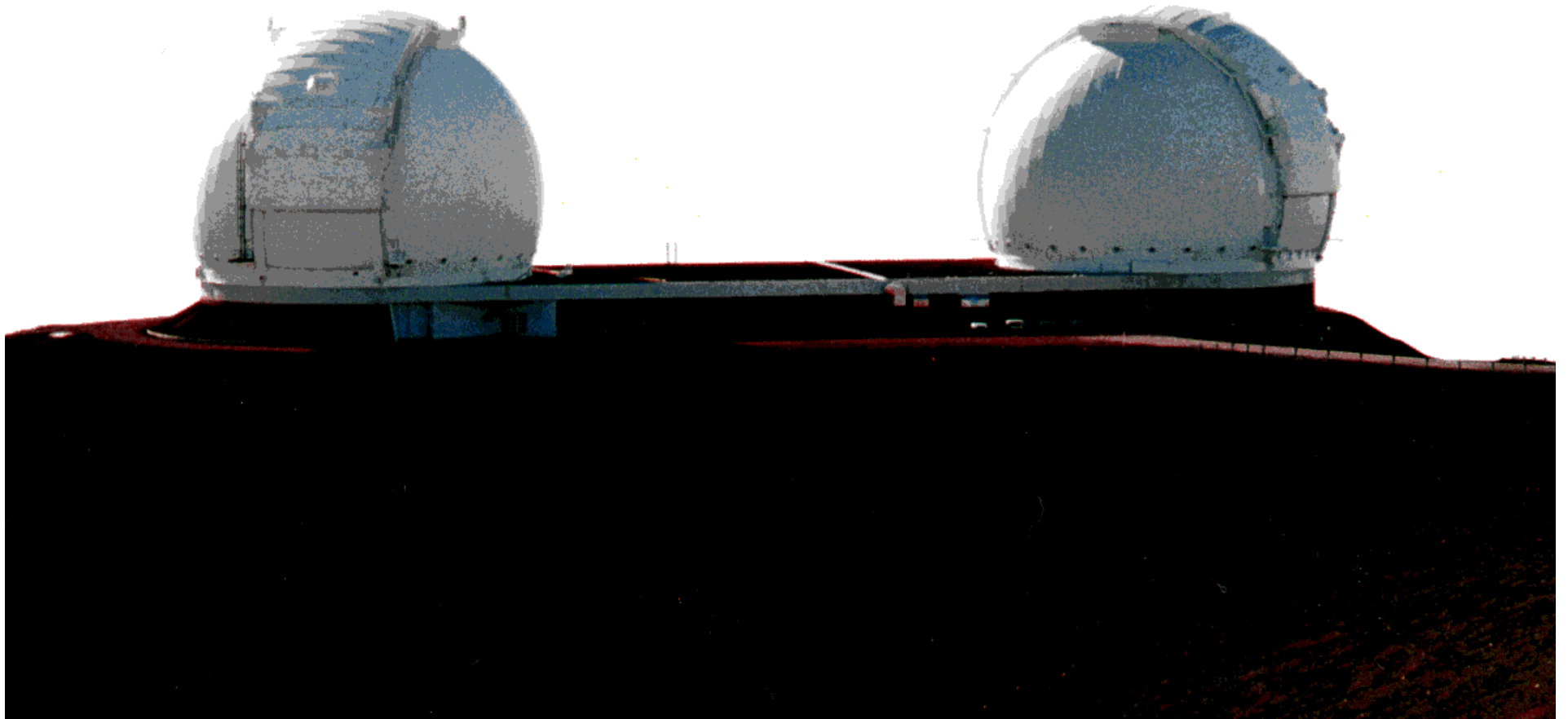
Primary Mirror is composed of 36 Hexagonal Segments

Segments: Zerodur, 1.8 m diameter, 75 mm thick, Weight = 880 lbs

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Photo: Keck Telescopes



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Photo: Keck Dome

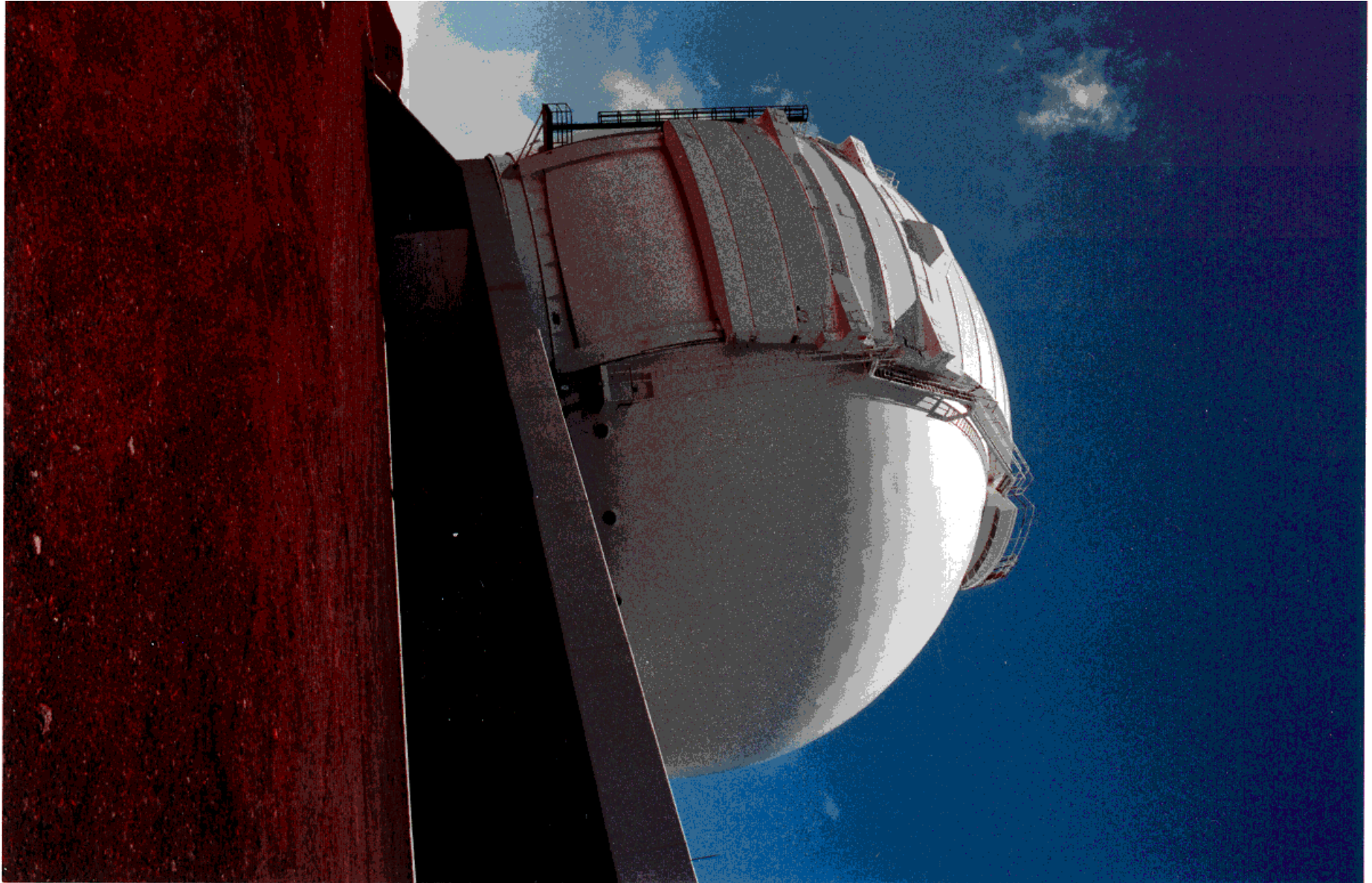
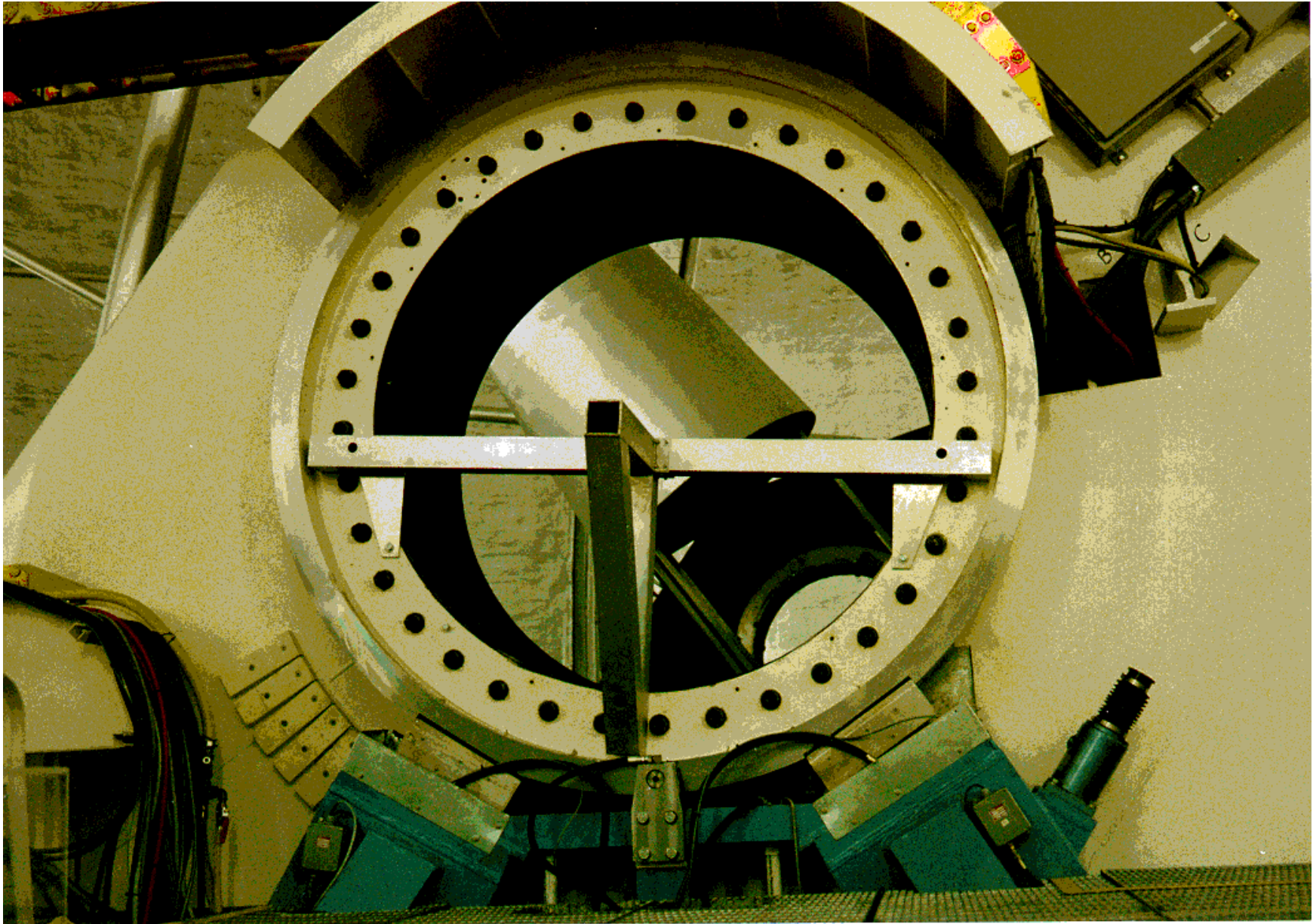


Photo: Keck Model



Photo: Experiment Support Structure

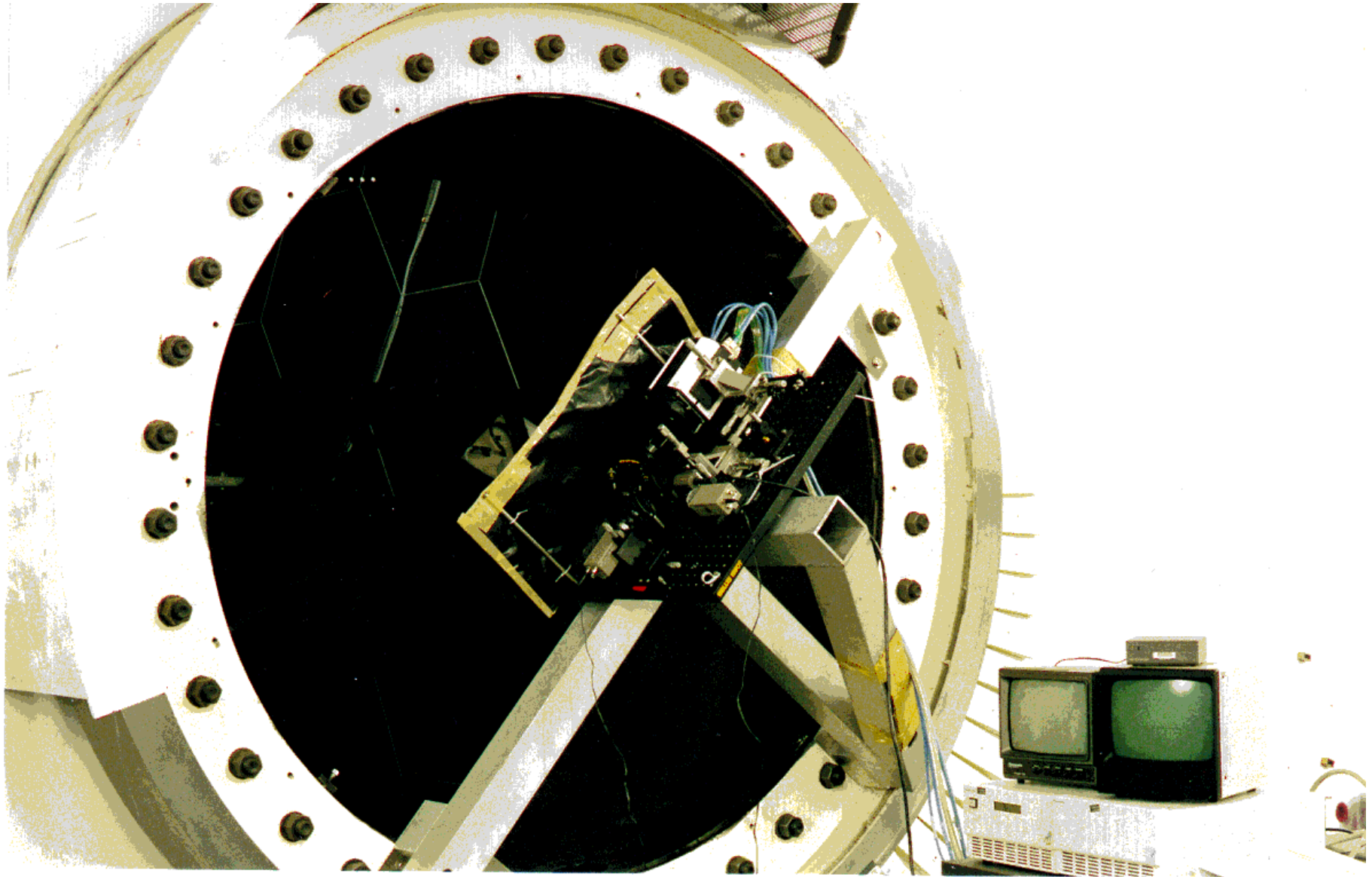


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Experiment on Support Structure on Left Nasmyth Platform of Keck II



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Photo: Optical Breadboard - Top View

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Photo: Optical Breadboard - Top Side View

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Photo: Keck Telescopes

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Photo: Keck Dome

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Photo: Keck Model

Advanced Technology Center



Photo: Experiment Support Structure

Advanced Technology Center



Experiment on Support Structure on Left Nasmyth Platform of Keck II
